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Sommario/riassunto

Your road map for meeting today's digital testing challengesToday, digital logic devices are common in products that impact public safety, including applications in transportation and human implants. Accurate testing has become more critical to reliability, safety, and the bottom line. Yet, as digital systems become more ubiquitous and complex, the challenge of testing them has become more difficult. As one development group designing a RISC stated, ""the work required to . . . test a chip of this size approached the amount of effort required to design it."" A valued reference for near